

Supporting Information

The Fabrication of Self-Powered CuInS₂/TiO₂ Heterojunction Photodetector and the Application in Visible Light Communication with Ultraviolet Light Encryption

Menghan Li, Jianping Xu,* Kuifeng Zhu,* Shaobo Shi, Qiuyang Zhang, Yichen Bu,
Jing Chen, Jianghua Xu, Qin Zheng, Yanjie Su, Xiaosong Zhang, and Lan Li*

School of Science, Tianjin University of Technology, Tianjin 300384, China.

Tianjin FLY Technology Company Limited, Tianjin 300385, China

School of Science, Key Laboratory of Display Materials and Photoelectric Devices,
Ministry of Education and Tianjin Key Laboratory for Photoelectric Materials and
Devices, Tianjin University of Technology, Tianjin 300384, China.

School of Science, Tianjin University of Technology and Education, Tianjin 300222,
China

*E-mail: xjp0335@163.com (Jianping Xu)

*E-mail:18622029890@126.com (Kuifeng Zhu)

*E-mail:lilan2000us@126.com (Lan Li)

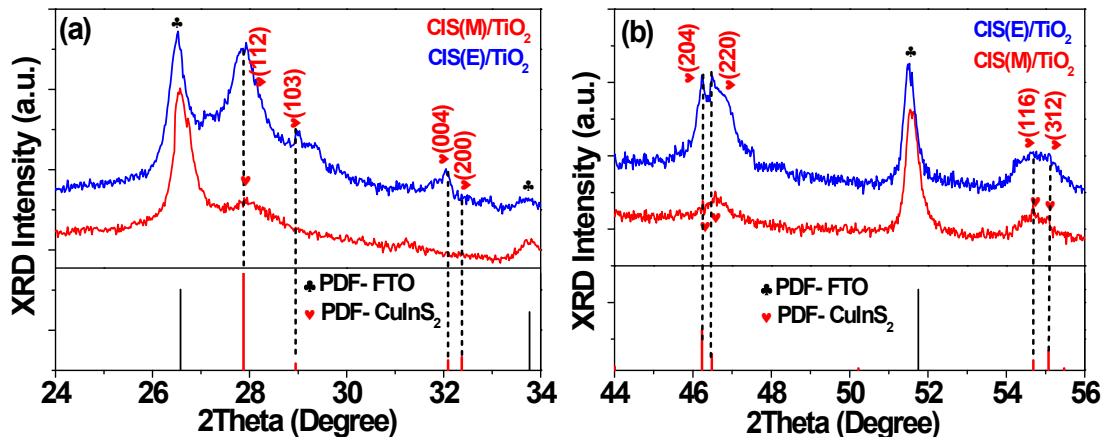


Fig.S1 Enlarged view of CIS XRD patterns for (a) (112), (103), (004) and (200) crystal planes, and (b) (204), (220), (116) and (312) crystal planes

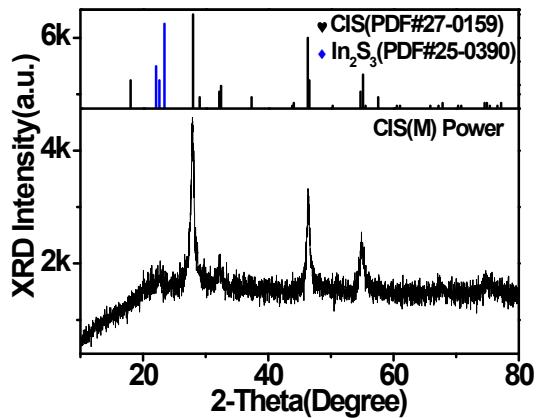


Fig.S2 XRD pattern of CIS powder grown in mixed solvent

Fig.S2 shows the XRD pattern of CIS powder grown in mixed solvent. Except for the weak diffraction peak of In₂S₃ at $2\theta=22.5^\circ$ (PDF#25-0390), all other peaks are single chalcopyrite CIS(PDF#27-0159). The solubility product k_{sp} of In₂S₃ is 5.7×10^{-74} and the solubility product k_{sp} of Cu₂S is 3×10^{-48} . Because the solubility product of In₂S₃ is smaller than Cu₂S, and the In³⁺concentration in the reaction precursor solution

is larger than Cu^+ , the growth rate of In^{3+} in the early stage of reaction is larger than Cu^+ , which results in the proportion of In being greater than Cu during the growth process, and In_2S_3 impurities are more likely to be generated.

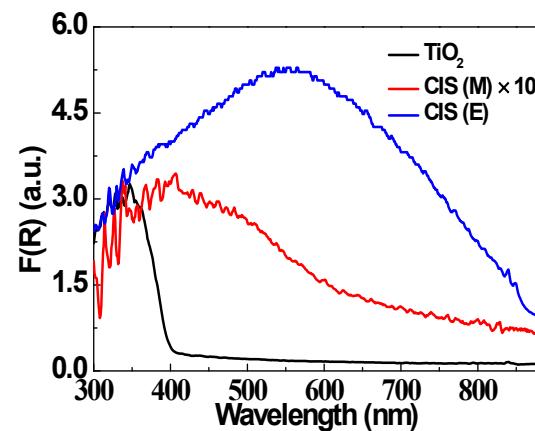


Fig.S3 F(R) spectra in incident light with different wavelengths

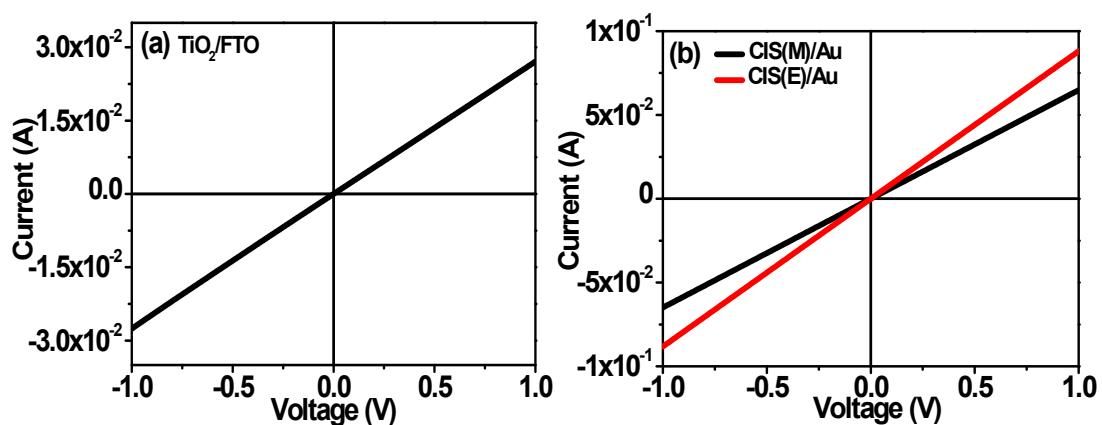


Fig.S4 I-V curves of (a) FTO/TiO₂ and (b) CIS/Au

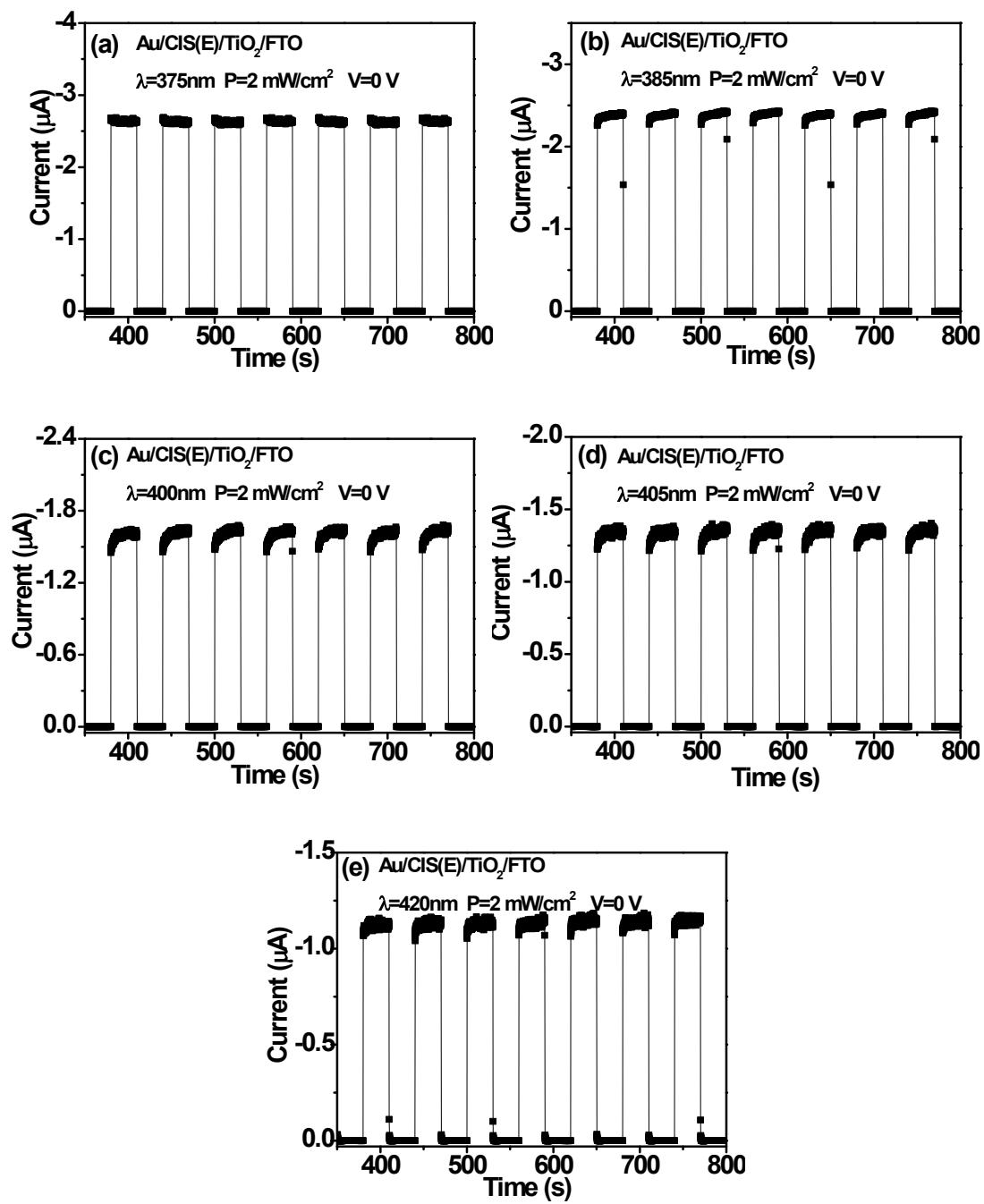


Fig.S5 I-t cycle curves of CIS(E)/TiO₂ heterojunction device under different wavelength illumination

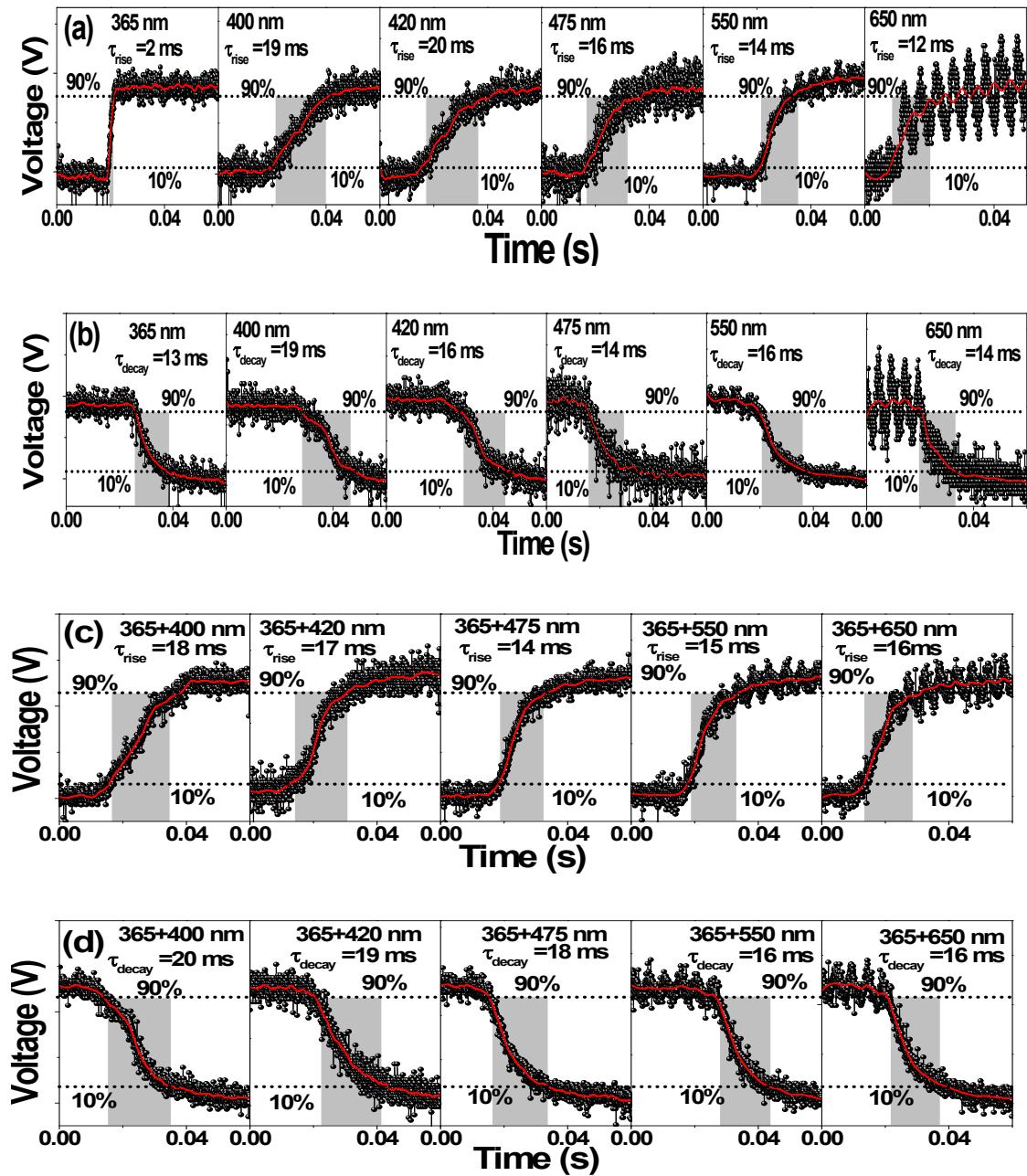


Fig.S6 (a) Response time and (b) Decay time of CIS(E)/TiO₂ heterojunction PD under

monochromatic light irradiation. (c) Response time and (d) Decay time under simultaneous irradiation of UV (365 nm) and visible light with different wavelengths

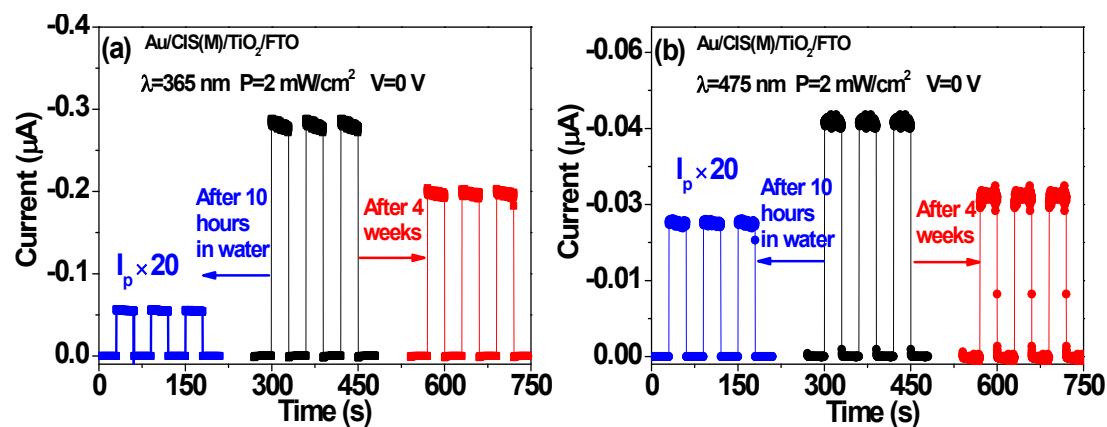


Fig.S7 The poor stability of CIS(M)/TiO₂ heterojunction PD under (a) 365 nm and (b) 475 nm light illumination

Table S1. Cu/In ratio of the CIS films at surface and bulk

Samples	Cu/In Ratio	Cu/In Ratio
	Surface (XPS)	Bulk (EDS)
CIS(M)/TiO ₂	0.44	0.72
CIS(E)/TiO ₂	0.83	0.98

Table S2. Information about TiO₂ NRs and CIS films obtained from XPS and M-S spectra

Samples	N _D (cm ⁻³)	N _A (cm ⁻³)	V _{FB} (V)	VB (eV)
TiO ₂	4.67×10 ¹⁹	--	-0.69	2.62
CIS(M)	--	8.23×10 ¹⁹	0.03	0.93
CIS(E)	--	6.01×10 ²⁰	-0.25	0.68

Photodetector	Wavelength h (nm)	Bias (V)	D* (Jones)	R (mA/W)	I _{ph} /I _d	T _r (ms)	Ref.
Organics/CIS-							
ZnS Core-Shell	450	-40 (V _{GS})	3.76×10 ¹¹	860	120	< 5	16
QDs/Organics							
SiO ₂ /CIS-ZnS							
Core-Shell QDs -	660 (5 mW)	V _{DS}	--	35×10 ³	--	--	19
graphene/Au							
ITO/ZnO-CIS	620						
QDs/TFB/PED	(14.2	0	2.5×10 ¹⁰	0.53	--	--	20
OT:PSS/Al	mW/cm ²)						
Si/SiO ₂ /MoS ₂ /CIS	635	4.5 (V _{DS})	2.27×10 ¹²	16.65×10 ³	24.1	5×10 ²	21
QDs/AuNPs							
ITO/TiO ₂ /PV							

K:CIS-ZnS								
QDs/MoO ₃ /Ag								
Si/SiO ₂ /CIS-								
ZnS	980	25	--	--	--	--	--	23
QDs/UCNP								
FTO/TiO ₂ /CIS /Au	365 (2 mW/cm ²)	0	1.3×10 ¹²	44.8	2.7×10 ⁴	2	This work	
FTO/TiO ₂ /CIS /Au	650 (2 mW/cm ²)	0	4.7×10 ¹¹	15.6	9.2×10 ³	12	This work	

Table S3. Performance parameters based on CIS PDs